

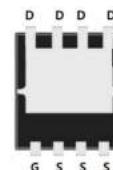


Features

- N-Channel
- Low grid charge
- Low reverse transmission capacitance
- Fast switching speed
- Pb-free lead plating
- 100% EAS Tested

V_{DS}	40	V
$R_{DS(on),TYP}$ @ $V_{GS}=10$ V	0.8	mΩ
I_D	270	A

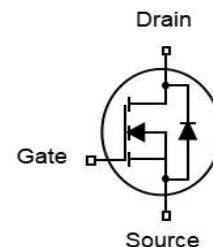
DFN5x6



RoHS



Part ID	Package Type	Marking	Packing
ZTG009N04GC	DFN5x6	ZTG009N04GC	5000pcs/Reel



Absolute Maximum Ratings $T_A = 25^\circ\text{C}$, unless otherwise specified

Symbol	Parameter	Rating	Unit	
Common Ratings (Tc=25°C Unless Otherwise Noted)				
V_{GS}	Gate-Source Voltage	± 20	V	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	40	V	
T_J	Maximum Junction Temperature	150	°C	
T_{STG}	Storage Temperature Range	-55 to 150	°C	
I_{DM}	Drain Current-Continuous@ Current-Pulsed	$T_c = 25^\circ\text{C}$	1080	A
Mounted on Large Heat Sink				
I_D	Drain Current-Continuous	$T_c = 25^\circ\text{C}$	270	A
		$T_c = 100^\circ\text{C}$	171	A
I_{AS}	Single pulse avalanche Current	49	A	
P_D	Maximum Power Dissipation	119	W	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	1.05	°C/W	
$R_{\theta JA}$	Thermal Resistance Junction-Ambient (Note 3)	50	°C/W	
Drain-Source Avalanche Ratings				
EAS	Avalanche Energy, Single Pulsed (Note 5)	600	mJ	



Electrical Characteristics ($T_J=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Electrical Characteristics @ $T_J=25^\circ C$ (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
Idss	Zero Gate Voltage Drain Current	$V_{DS}=40V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	μA
		$V_{DS}=40V, V_{GS}=0V, T_J=125^\circ C$	--	4	--	μA
IGSS	Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2.4	--	3.4	V
RDS(on)	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=50A$	--	0.8	0.95	$m\Omega$

Dynamic Electrical Characteristics @ $T_J = 25^\circ C$ (unless otherwise stated) (Note 4)

Ciss	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1MHz$	--	6390	--	pF
Coss	Output Capacitance		--	1930	--	pF
Crss	Reverse Transfer Capacitance		--	50	--	pF
Rg	Gate Resistance	f=1MHz	--	1.3	--	Ω
Qg	Total Gate Charge	$V_{DD}=32V, I_D=50A, V_{GS}=10V$	--	96	--	nC
Qgs	Gate-Source Charge		--	32	--	nC
Qgd	Gate-Drain Charge		--	24	--	nC

Switching Characteristics

Td(on)	Turn-on Delay Time	$V_{DD}=32V, I_D = 50A, R_G=2.5\Omega, V_{GS}=10V$	--	27	--	ns
Tr	Turn-on Rise Time		--	37	--	ns
Td(off)	Turn-Off Delay Time		--	64	--	ns
Tf	Turn-Off Fall Time		--	24	--	ns

Source-Drain Diode Characteristics @ $T_J = 25^\circ C$ (unless otherwise stated)

Is	Diode Forward Current (Note 2)		--	--	270	A
VSD	Forward on voltage (Note 3)	$I_S=50A, V_{GS}=0V$	--	--	1.4	V
Trr	Reverse Recovery Time	$T_J=25^\circ C, I_S=50A, V_R=40V, di/dt=100A/\mu s$	--	79	--	ns
Qrr	Reverse Recovery Charge		--	145	--	nC

- The rating only refers to the maximum absolute value of $25^\circ C$ in the specification. If the shell temperature is higher than $25^\circ C$, it needs to be derated according to the actual environmental conditions.
- Pulse time $5\mu s$, pulse width is limited by the maximum junction temperature.
- The dissipated power value will change with the change of temperature, when greater than $25^\circ C$, the dissipated power value will decrease by $1.11 W/^\circ C$ with the increase of $1^\circ C$ of temperature.
- Pulse test: pulse width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
- EAS condition: $T_J=25^\circ C, V_{DD}=32V, V_G=10V, L=0.5mH, R_G=25\Omega$.

Typical Electrical and Thermal Characteristics

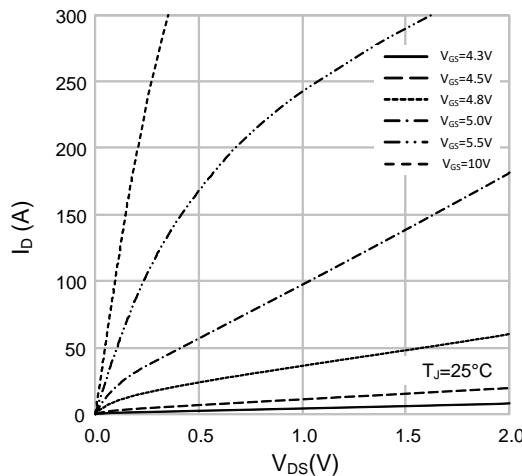


Figure 1 Output Characteristics

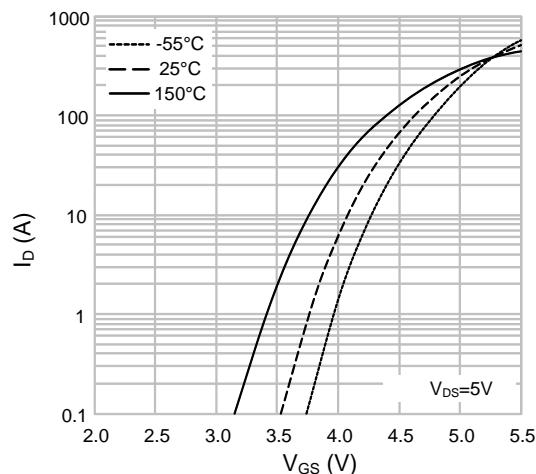


Figure 4 Transfer Characteristics

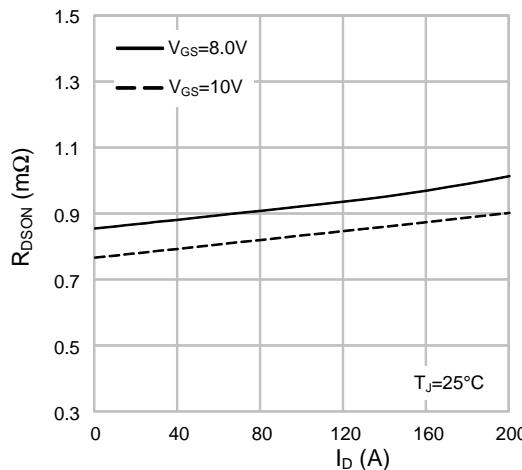


Figure 2 Rdson VS Drain Current

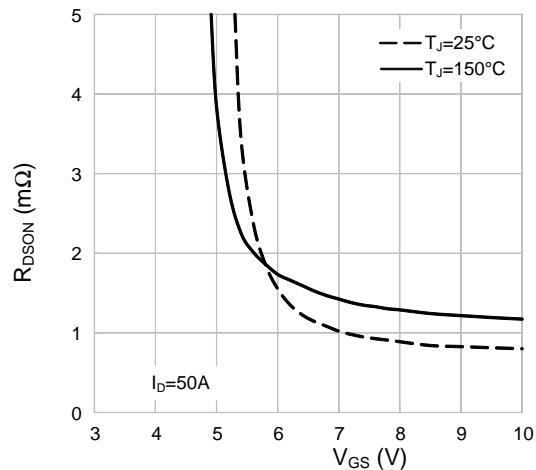


Figure 5 Rdson VS VGS

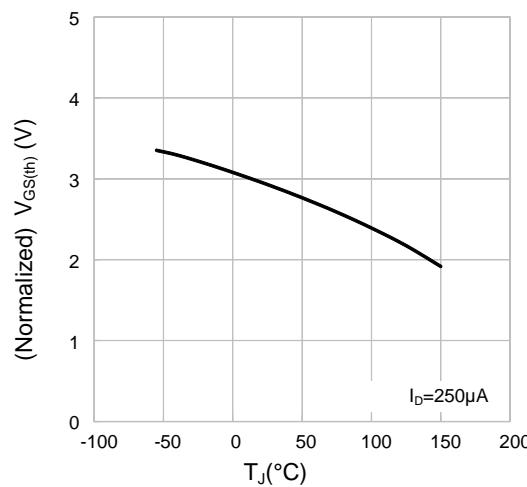


Figure 3 VGS(th) VS Junction Temperature

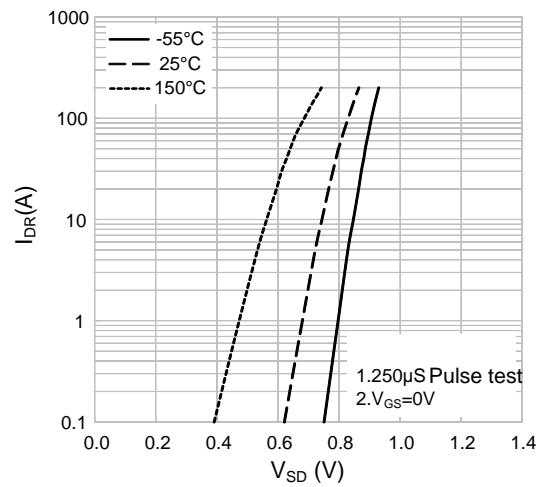


Figure 6 Body Diode Forward Voltage Drop VS Source Current and Temperature

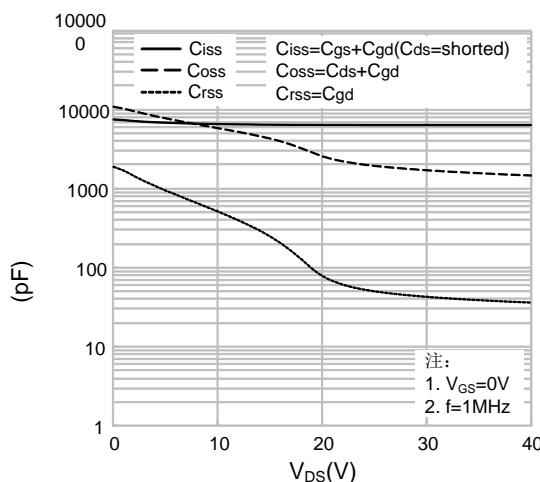


Figure 7 Capacitance Charateristics

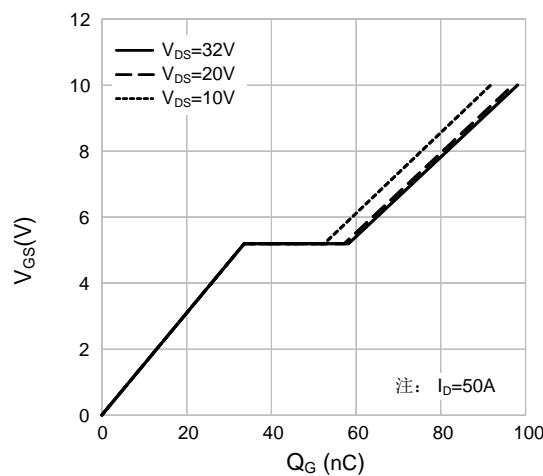


Figure 10 Gate Charge

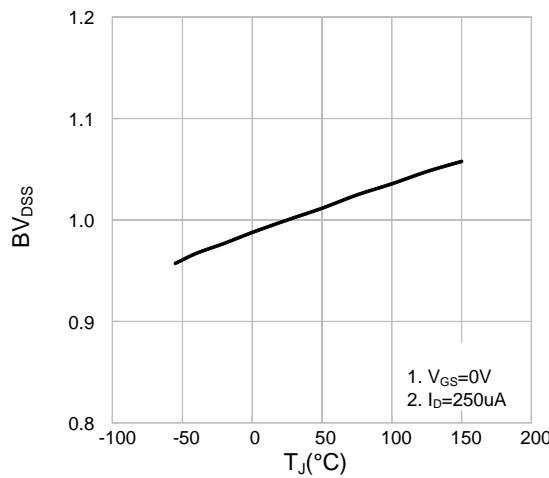


Figure 8 Breakdown Voltage VS Temperature Characteristic

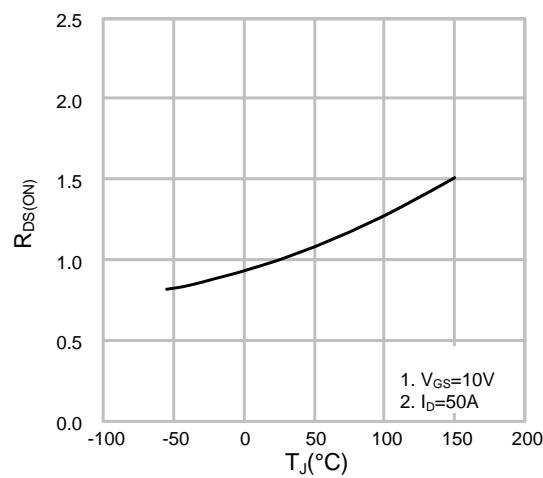


Figure 11 R_ds(on) VS Temperature Characteristic

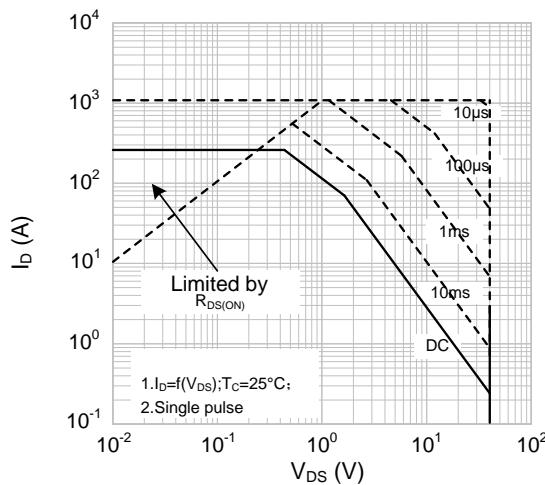


Figure 9 Safe Operation Area

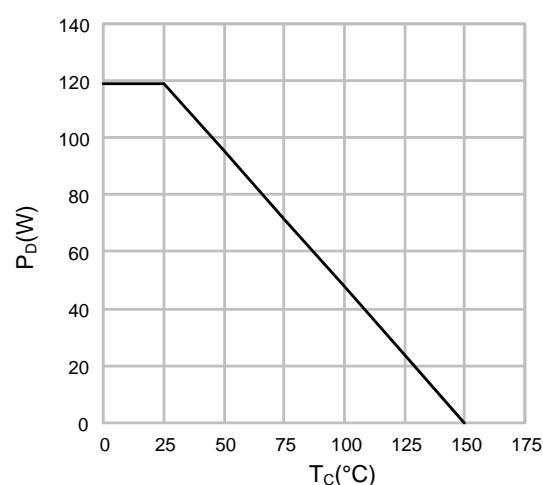


Figure 12 Power Dissipation VS Case Temperature

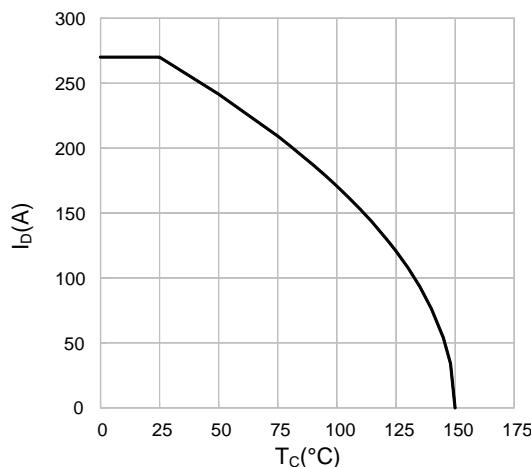


Figure 13 Drain Current VS Case Temperature

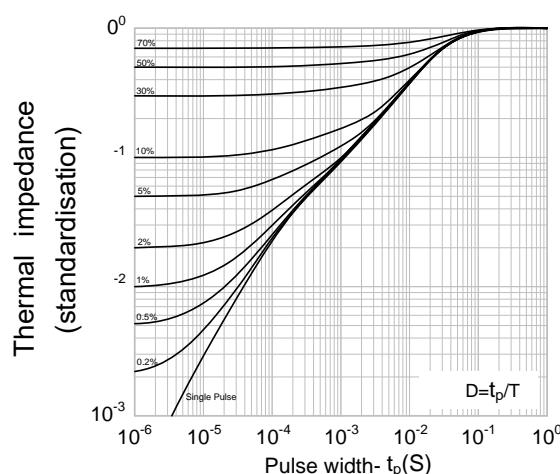
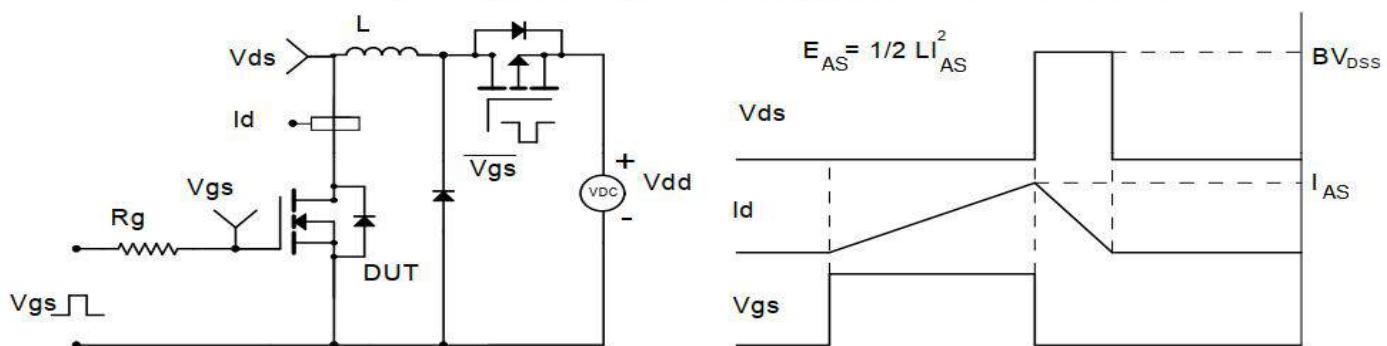


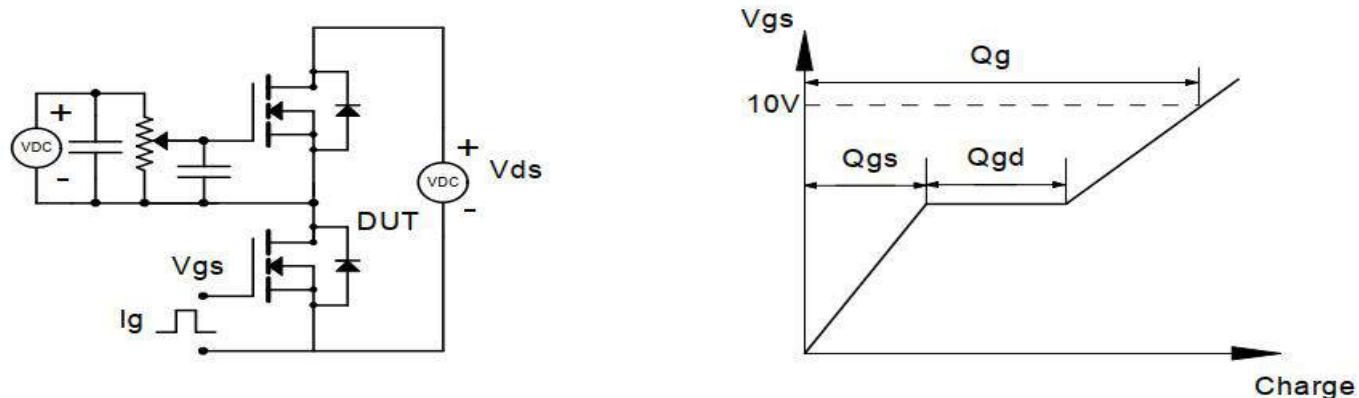
Figure 14 Transient Heat Value Reactance VS Pulse Width

Test circuit&Waveform

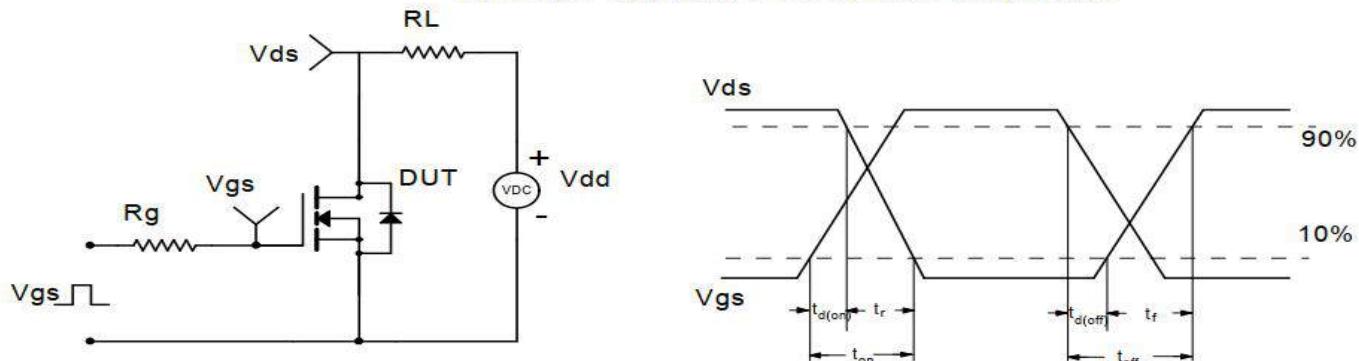
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



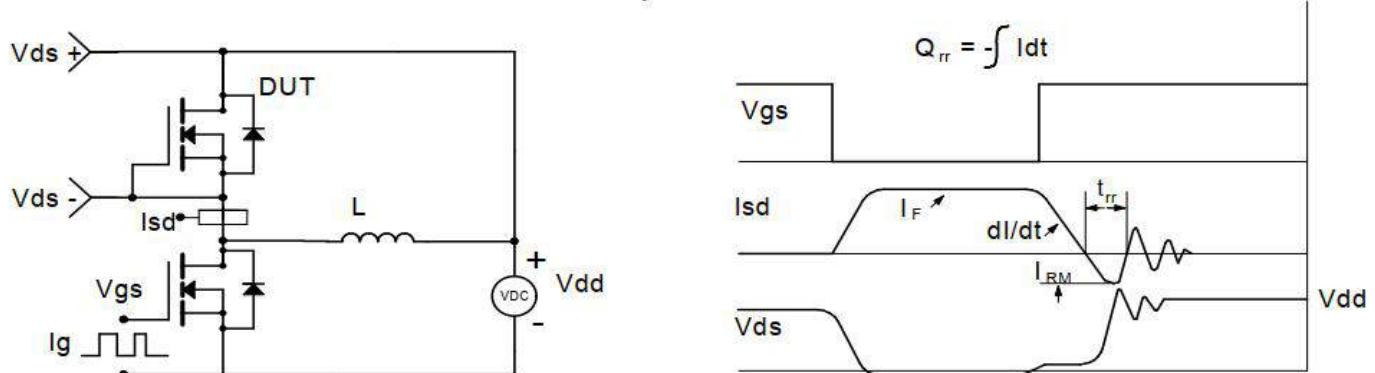
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

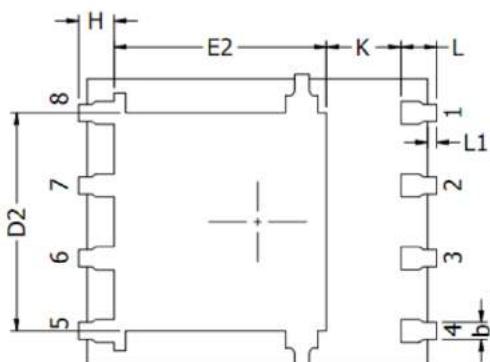


Diode Recovery Test Circuit & Waveforms

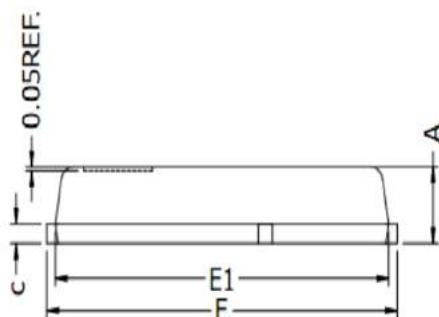
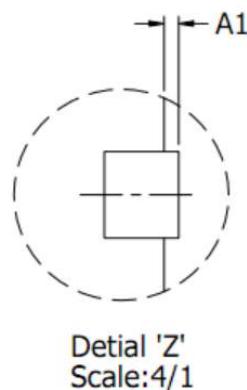
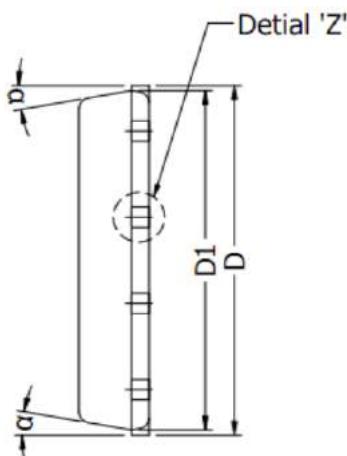
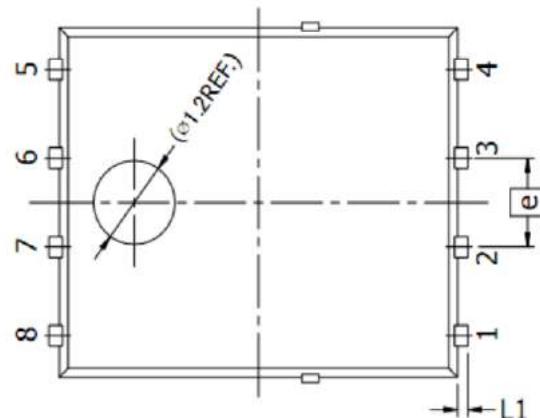




DFN5x6-8L Package Information



BACKSIDE VIEW



DIM.	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.10
A1	0	-	0.05
b	0.30	0.40	0.50
c	0.20	0.25	0.30
D	5.15 BSC		
D1	5.00 BSC		
D2	3.76	3.81	3.86
E	6.15 BSC		
E1	5.80	5.85	5.90
E2	3.45	3.65	3.85
e	1.27 BSC		
H	0.51	0.61	0.71
K	1.10	-	-
L	0.51	0.61	0.71
L1	0.08	0.15	0.23
a	10°	11°	12°

Customer Service

Sales and Service:

zj@ztasemi.com